

(12) **United States Patent**
Liou et al.

(10) **Patent No.:** **US 9,410,902 B1**
(45) **Date of Patent:** **Aug. 9, 2016**

(54) **OVERLAY MEASUREMENT METHOD**

(56) **References Cited**

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(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 0 days.

(21) Appl. No.: **14/703,890**

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(22) Filed: **May 5, 2015**

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(51) **Int. Cl.**
G01B 11/14 (2006.01)
G01N 21/95 (2006.01)
G01B 11/27 (2006.01)
G01N 21/88 (2006.01)

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(52) **U.S. Cl.**
CPC **G01N 21/9501** (2013.01); **G01B 11/27** (2013.01); **G01N 21/8806** (2013.01); **G01N 2021/8825** (2013.01)

(57) **ABSTRACT**

An overlay measurement method includes providing three predetermined patterns, including a first predetermined pattern, a second predetermined pattern and a third predetermined pattern. An inspection process is then performed on said three predetermined patterns, to obtain three image points, including a first image point, a second image point and a third image point respectively. Next, a defining process is performed to define a default position, and a calculating process is performed to obtain a real offset value $x=(p-q)*(c-a)/(a-b)+p$.

(58) **Field of Classification Search**
CPC G06K 9/00; G06K 9/36; G01N 21/95; G01N 21/27; G01N 21/88
See application file for complete search history.

16 Claims, 3 Drawing Sheets

